1522/204 1602/204 MICROELECTRONICS, ELECTRICAL PRINCIPLES II, INSTRUMENTS AND ELECTRONIC FAULT DIAGNOSIS June/July 2023

Time: 3 hours



THE KENYA NATIONAL EXAMINATIONS COUNCIL

CRAFT CERTIFICATE IN ELECTRICAL AND ELECTRONIC TECHNOLOGY (TELECOMMUNICATION OPTION)

MODULE II

MICROELECTRONICS, ELECTRICAL PRINCIPLES II, INSTRUMENTS AND ELECTRONIC FAULT DIAGNOSIS

3 hours

INSTRUCTIONS TO CANDIDATES

You should have the following for this examination:

Answer booklet;

Non-programmable scientific calculator;

Mathematical tables:

Intel 8080/8085 instruction set;

Drawing instruments.

This paper consists of EIGHT questions in THREE sections; A, B and C.

Answer ONE question from section A, TWO questions from section B and TWO questions from section C in the answers booklet provided.

All questions carry equal marks.

Maximum marks for each part of a question are as indicated.

Candidates should answer the questions in English.

This paper consists of 9 printed pages.

Candidates should check the question paper to ascertain that all the pages are printed as indicated and that no questions are missing.

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SECTION A: MICROELECTRONICS

Answer ONE question from this section.

- (a) (i) Distinguish between software and hardware with respect to microprocessor systems.
 - (ii) Describe each of the following buses in a microprocessor:
 - I. control bus;

II. data bus.

(6 marks)

(b) State **four** features of the pentium microprocessor family.

(4 marks)

(c) Figure 1 shows the pin diagram of the 8085 microprocessor IC.



Fig. 1

(i) Explain the function of each of the following pins:

I. 32

II. 34

III. 3

IV. 5

(ii) Identify the pins for each of the following:

I. power supply;

II. data bus. (10 marks)

- 2. (a) Define each of the following with respect to memories:
 - (i) volatile;
 - (ii) random access;
 - (iii) address.

(6 marks)

(b) Draw a schematic block diagram to show how a 64K × 8 PROM can be realised from two 32K × 8 PROM chips. (9 marks)

(c) Write an assembly language program to add 16 H to 34 H and save the result in register D. (5 marks)

SECTION B: ELECTRICAL PRINCIPLES II

Answer TWO questions from this section.

- 3. (a) (i) State two advantages of digital-over analogue instruments.
 - (ii) Figure 2 shows a block diagram of a digital voltmeter.

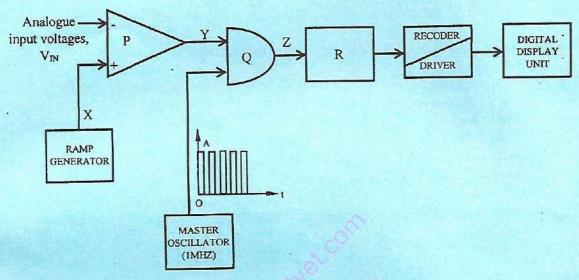


Fig. 2

- I. Identify the blocks marked P, Q and R.
- II. Sketch the waveforms at points X, Y and Z.

(11 marks)

- (b) Explain the function of each of the following in analogue indicating instruments:
 - (i) controlling torque;
 - (ii) damping torque.

(4 marks)

- (c) A voltmeter of resistance 100 Ω reads 1.47 V when connected across a dry cell. A potentionmeter is used to measure the e.m.f of the dry cell and balance is obtained at 73 cm with dry cell and 50 cm with a standard cell. The standard cell has an e.m.f of 1.018 V. Determine the:
 - (i) e.m.f of the dry cell;
 - (ii) internal resistance of the dry cell.

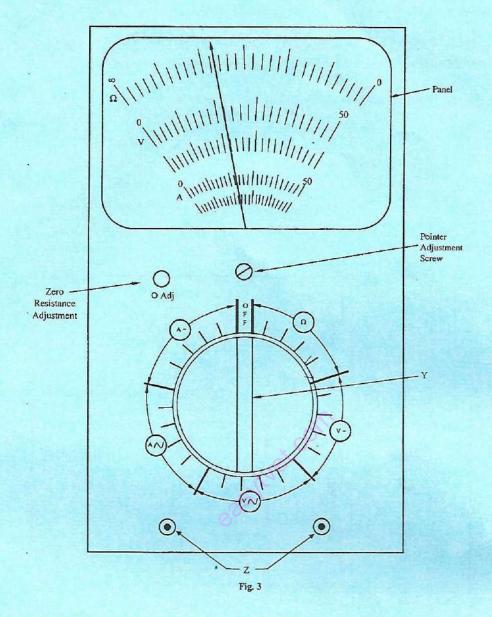
(5 marks)

4.	(a)	Define each of the following with respect to alternating current (a.c) generation:											
		(ii) cycle;											
		(iii) waveform.	(6 marks)										
	(b)	A rectangular coil has 40 runs and measures 30 cm by 20 cm. It is rotated at a speed of 1500 r.p.m in a uniform magnetic field of flux density 0.075 Wb/m². The axis of rotation is at right angles to the direction of the flux. Determine the:											
		(i) angular frequency, in rad/sec;											
		(ii) maximum value of flux;											
		(iii) maximum value of induced e.m.f.	(8 marks)										
	A 3-phase star connected generator supplies a 3-phase balanced delta-connect. The generator line voltage is 400 V.	ted load.											
		(i) Draw the circuit diagram for the connection.											
		(ii) Determine the phase voltage of the generator.	(6 marks)										
5.	(a)	A voltage, $v=340\sin\omega t$, is applied to a circuit and the resulting current is $i=14\sin(\omega t-30^\circ)$. For the circuit, determine the:											
		(i) impedance;											
		(ii) resistance;											
		(iii) reactance;											
		(iv) power;											
			(10 marks)										
	(b)	A 15 $\mu\mathrm{F}$ capacitor is charged to 200 V through a 1.2 M Ω resistor. Determin	e the:										
		(i) time constant;											
		(ii) initial charging current;											
		(iii) initial rate of rise of voltage across capacitor;											
		(iv) voltage across capacitor after 4.5 seconds from zero;											
		(v) time taken for the capacitor to be fully charged.	(10 marks)										

SECTION C: INSTRUMENTS AND ELECTRONIC FAULT DIAGNOSIS

Answer any TWO questions from this section.

6.	(a)	Define each of the following with respect to test signals:									
		(i) amplitude;									
		(ii) rise time; (iii) period. (6 r	marks)								
	(b)	(i) Sketch the waveform of a double sideband amplitude modulated wave,									
		assuming sinusoidal modulation.									
		(ii) The waveform in (b)(i) has a maximum value of 16 V and a minimum value 4 V. Determine the depth of modulation. (6 r	ue of marks)								
	(c)	A pulse waveform displayed on an oscilloscope has an amplitude of 15 V and a frequency of 6.25 KHz. The oscilloscope sensitivity settings are 10 V/cm and 20 μ s/cm. Determine the:									
		(i) number of peak-to-peak cm occupied on the vertical axis;									
		(ii) period of the wave;									
		(iii) number of cm occupied by one cycle of the wave on the horizontal axis. (81)	marks)								
7/	(a)	Explain parallax error in measurements and state how it can minimized. (3 t	marks)								
	(b)	Figure 3 shows a diagram of the front panel of an analogue multimeter.									
		(i) Identify and state the function of the parts labelled X, Y and Z.									
		(ii) State the meaning of the labels $V-$, $A\sim$ and Ω on the meter. (9)	marks								



- (c) Draw a labelled block diagram of a spectrum analyzer and describe its operation. (8 marks)
- 8. (a) (i) State **three** causes of premature failure in semiconductor devices.

 (ii) State **three** precautions to take when testing digital integrated circuits.

 (6 marks)
 - (b) Outline the procedure of testing a single-phase iron-cored transformer using an ohmmeter. (5 marks)

- (c) Figure 4 shows a circuit diagram of a common-emitter transistor amplifier. The base emitter voltage $V_{bc} = 0.7 V$ and the collector current $I_c = 3mA$.
 - (i) Estimate the bias voltages at the test points:

 TP_1

TP₂

TP₃

(ii) State the voltages at each test point when the resistor R₁ is open circuited.

(9 marks)

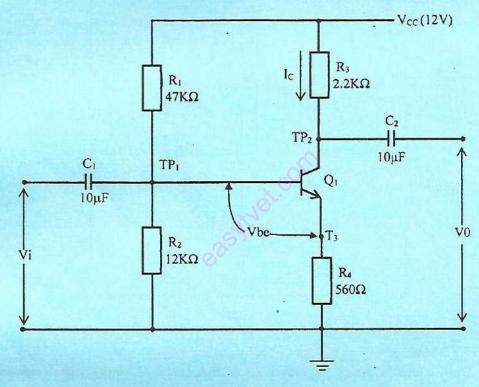


Fig. 4

Instruction set of

8080/8085

OP CODE	MNEM	ONIC	OP	MNEI	MONIC	OP	MNEMONIC	OP	MNEM	ONIC	OP	MNEM	ONIC	OP CODE	MNEM	IONIC
00	NOP		28	DCX	H	56	MOV D,M	81	ADD	C	ΛC	XRA	H	D7	RST	2
01	LX1	B,D16	2C	INR	L	57	MOV D,A	82	ADD	D	AD	ARX	L	D8	RC	
02	STAX	8	20	DCR	L	58	MOV E,8	83	ADD	E	AE	XRA	M	D9	-	
03	INX	В	2E	MVI	L,D8	59	MOV E,C	84	ADD	H	AF	XRA	A	DA	JC	Adr
04	INR	8	2F	CMA		5A	MOV E,D	85	ADD	L	80	ORA	В	08	IN	D8
05	DCR	В	30	SIM		58	MOV E.E	86	ADD	M	B1	ORA	C	DC	CC	Adr
06	MVI	8,08	31	LXI	SPD 16	5C	MOV E,H	87	ADD	А	82	ORA	0	DD	-	
07	RLC		32	STA	Adr	5D	MOV E,L	88	ADC	8	83	ORA	E	DE	SBI	D8
08	-		33	INX	SP	5E	MOV E,M	89	ADC	C	84	ORA	H	DF	RST	3
09	DAD	В	34	INR	M	5F	MOV E,A	8A	ADC	D	B5	ORA	L	E0	RPO	
OA .	LDAX	В	35	DCR	M	60	MOV H'B	88	ADC	E	B6	ORA	М	EI	POP	H
08	DCX	8	36	MV!	M.D8	61	MOV H,C	8C	ADC	Н	B7	ORA	A	E2	JPO	Adr
oc	INR	C	37	STC		62	MOV H,D	80	ADC	L	88	CMP	В	E3	XTHL	
00	DCR	C	38			63	MOV H,E	8E	ADC	M	89	CMP	C	E4	CPO	Adr
0E	MVI	C,08	39	DAD	SP	64	MOV H,H	8F	ADC	A	BA	CMP	D	E5	PUSH	11
OF	RAC		3A	LDA	Adr	65	MOV H,L	8G	SUB	В	BB	CMP	E	E6	ANI	08
10			38	DCX	SP	66	MOV H,M	91	SUB	C	BC	CMP	11	E7	RST	4
11	LXI	D,D16		INA	A	67	MOV H,A	92	SUB	D	80	CMP	L	E8	RPE	
12	i de la constante de la consta	D	30	DCR	A 000	68	MOV L,B	93	SUB	£	BE	CMP	M	E9	JPE JPE	Adr
13	INX	D	3E 3F	MVI	A.D8	69	MOV LC	94	SUB	H	BF C0	RNZ	A	EA EB	XCHG	
14	DCR	0	40	MOV	8,8	6A 6B	MOV L,E	96	SUB	M	C1	POP	В	EC	CPE	Adr
16	MVI	D,D8	41	MOV	B,C	6C	MOV L,E	97	SUB	A	C2	JNZ	Adr	ED		
17	RAL	0,00	42	MOV	B,O	60	MOV L,L	98	SBB	В	C3	JMP	Adr	EE	ERI	DB
18			43	MOV	B,E	6E	MOV L,M	99	SBB	C	C4	CNZ	Adr	EF	RST	5
19	DAD	D	44	MOV	8,8	6F	MOV LA	9A	S88	D	C5	PUSH	В	FO	RP	
1A	LDAX	-	45	MOV	B,L	70	MOV M,B	9B	SBB	E	C6	ADI	DB	F1	POP	FSW
18	DCX	D	46	MOV	B.M	71	MOV M,C	90	588	н	C7	RST	0	F2	JP	Adr
10	INR	F	47	MOV	B,A	72	MOV M,D	90	SBB	L	C8	RZ.		F3	Di	
1D	DRC	Ε	48	VOM	C,B	73	MOV ME	98	SBB	M	C9	RET	Adr	F4	CP	Adr
18	MVI	E,D8	49	MOV	C.C	74	MOV M,H	9F	588	A	CA	JZ		F5	PUSH	PSW
1F	RAR		4A	MOV	C,D	75	MOV M,L	AO	ANA	В	СВ			F6	ORI	OB
20	RIM		48	MOV	C,E	76	HLT	A1	ANA	C	CC	CZ	Adr	F7	RST	6
21	LXI	H.D 18	4C	VOM	C,H	77	MOV M.A	A2	ANA	D	CD	CALL	Adr	F8	BM	
22	SHLD	Adr	40	MOV	C,L	78	MOV A,B	EA	ANA	Ε	CE	ACI	D8	F9	SPHL	
23	INX	н	45	MOV	C,M	79	MOV A.C	A4	ANA	H	CF	RST	1	FA	JM	Aris
24	INR	Н	4F	MOV	C,A	7A	MOV A,D	A5	ANA	L	DO	RNC		FB	E1	
25	DCR	4	50	MOV	D,B	78	MOV A,E	A6	ANA	M	DI	POP	D	FC	CM	Adr
26	MVI	8C,H	51	MOV	D,C	7C	MOV A,H	A7	ANA	Α	D2	JNC	Adr	FD		
27	DAA		52	MOV	D.D	70	MOV AL	A8	XRA	В	D3	OUT	DB	FE	CPI	D9
28	-		53	MOV		7E	MOV A,M	A9	XRA	C	D4	CNC	Adr	FF	BST	7
29	DAD		54	1	D.H	7F	MOV A,A	AA.	XRA		D5	PUSH				
2A	LHLD	Adr	55	MOV	D,L	80	ADD B	AB	XRA	E	D6	SUI	DB			

D8 = constant, or logical/arithmetic expression that evaluates to an 8-bit data quantity. D16 = constant, or logical/arithmetic expression that evaluates to a 16-bit data quantity. Adr = 16-bit address.

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